# **Recent Progress - Software**

#### **Software:**

- **SVT**: Work begun on WP agent, thanks to the collaboration with Angelina and Jelena first issues to familiarize with the code already in progress -> pushed and tested / not merged
- ITS3: The learning curve is slower, the task is broader, ideally, I would like to have some concrete ideas / proposals / commits sometime next week

# **Recent Progress – Wafer Probing**

## **Wafer Probing:**

- TWEPP plots and tests information have been added in a draft form to Overleaf
- A standalone Overleaf has been created for TWEPP proceeding to be shared soon,
  the aim is to bring it to a good shape by the end of the weekend (deadline for JINST is 6<sup>th</sup> November)
  is there any internal SVT / ITS3 review to go through before that? How?
- More tests on NKF7 wafer to be done to have larger statistics and improve the plots for the main paper, postponed to give priority to Software development
- Last Friday chat with Davide Ceresa (ESE IC designer) summary in next slide, TWEPP follow-up
- Brief chat with ESE lpgbt designer now working on Picopix for LHCb VELO (4x data out @25Gb/s) for which also WP might be interesting, to be followed up...
  it might be worth proposing to Federico an ESE-ME "Topical" for the whole community?

## **Coffee chat with Davide Ceresa**

**Approximate cost** that the group had to sustain to test **CMS outer tracker frontend ASICs:** (internal info – tracking EDH documents for precise reference in Notion work in progress)

1. Custom Probe cards design ~20k + manufacturing ~20k

**2. Testing system** (software test routines) ~ **200k** 

3. Testing time per wafer ~ 150/wafer ~1kwafers -> ~150k underestimated

+ shipping + visual inspection + storage...

Point 1) is inevitable, points 2), 3) could be significantly lowered testing internally

### **Coffee chat with Davide Ceresa**

On top of the economical advantage there could be some others:

- ASIC designers had to devote a lot of time to the Procurement aspects
- ESE engineers characterized initially the wafers themselves at CERN (cantilever probing)
   their data acquisition / testing system was completely redesigned for Production testing
   duplicated effort could be greatly optimized by working in synergy for characterization and Prod QC
- In depth studies of low-yield QC results are not easy to arrange with the industry -> in case further studies / characterization are needed during Prod QC, testing in house might be helpful

#### TAKEAWAY:

the group recognizes this WP development could have great benefits and would be interested to collaborate, **BUT** large production for CMS LS3 upgrades are finishing/ed, probably a chat with Federico could help to understand future prospects